

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination SHIROTA, HIROSHI	
		Examiner	Art Unit	Page 1 of 1
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*	B	US-5,787,114	07-1998	Ramamurthy et al.	375/221
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**NON-PATENT DOCUMENTS**

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	U	Takahiro Yamaguchi, Mani Soma, Masahiro Ishida, Hirobumi Musha and Louis Malarsie, "A new method for testing Jitter tolerance of SerDes devices using sinusoidal jitter", Advantest Laboratories, University of Washington, Advantest Corporation, Agere Systems, ITC International Test Conference, 2002 IEEE).
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.